AMENDMENTS TO THE CLAIMS

1-4. (cancelled)

5. (currently amended) The method of claim 4. A method for small signal
scusing during a read operation of a static random access memory (SRAM) cell, the
method comprising:
coupling a pair of complementary sense amplifier data lines to a
corresponding pair of complementary bit lines associated with the SRAM cell:
setting a sense amplifier so as to amplify a signal developed on said sense
amplifier data linos.
wherein said bit line pair remains coupled to said sense amplifier data
lines at the time said sense amplifier is set; and
configuring the SRAM cell with PFET access transistors so as to clamp
one of said pair of complementary sense amplifier data lines to a logic high voltage upon
activation of a word line associated with the SRAM cell;
. wherein said clamping is implemented through one of a pair of pull up
transistors within the SRAM cell, and
wherein said pair of pull up transistors within the SRAM cell has larger a
pull up strength relative to a pull down strength of a pair of pull down transistors within
the SRAM cell.

6. (currently amended) The method of claim-15, wherein said pair of complementary sense amplifier data lines is coupled to said corresponding pair of complementary bit lines through a pair of activated bit switches.

7-10. (cancelled)

11. (currently amended) The method of claim 10,-A method for implementing a
read operation for a static random access memory (SRAM) cell, the method comprising:
activating a word line associated with the SRAM cell;
deactivating a precharge circuit configured for precharging a pair of
complementary bit lines associated with the SRAM cell;
coupling a corresponding pair of complementary sense amplifier data lines
to said pair of complementary bit lines associated with the SRAM cell;
setting a sense amplifier so as to amplify a signal developed on said sense
amplifier data lines,
wherein said bit line pair remains coupled to said sense amplifier data
lines at the time said sense amplifier is set; and
configuring the SRAM cell with PFET access transistors so as to clamp
one of said pair of complementary sense amplifier data lines to a logic high voltage upon
activation of a word line associated with the SRAM cell;
wherein said clamping is implemented through one of a pair of pull up
transistors within the SRAM cell, and
wherein said pair of pull up transistors within the SRAM cell has larger a
pull up strength relative to a pull down strength of a pair of pull down transistors within
the SRAM cell.

12. (currently amended) The method of claim-711, wherein said pair of complementary sense amplifier data lines is coupled to said corresponding pair of complementary bit lines through a pair of activated bit switches.

13-16. (cancelled)

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17. (currently amended) The apparatus of claim 16, An apparatus for small
signal sensing during a read operation of a static random access memory (SRAM) cell,
comprising:
a pair of complementary sense amplifier data lines selectively compled to a
corresponding pair of complementary bit lines associated with the SRAM cell;
a sense amplifier configured to amplify a signal developed on said sense
amplitier data lines,
wherein said bit line pair is coupled to said sense amplifier data lines
whenever said sense amplifier is set; and
a pair of PFET access transistors associated with the SRAM cell, said
PFET access transistors configured to clamp one of said pair of complementary sense
amplifier data lines to a logic high voltage upon activation of a word line associated with
the SRAM cell;
said clamp further implemented through one of a pair of pull up transistors
within the SRAM cell; and
wherein said pair of pull up transistors within the SRAM cell has larger a
pull up strength relative to a pull down strength of a pair of pull down transistors within
the SRAM cell,

18. (currently amended) The apparatus of claim-1317, wherein said pair of complementary sense amplifier data lines is coupled to said corresponding pair of complementary bit lines through a pair of activated bit switches.